Electronic Version
Stylesheet Version v1.1.1

Claims

[c1] 1. A method for generating a process aid on a wafer, the method comprising the steps of:

entering a process technology and a process aid type to be built into a program;

reading technology design rules and process aid parameters for the process aid type into the program;

accessing a process aid instruction file to attain instructions for building the process aid; and

building the process aid in on the wafer using the instructions based on the technology design rules and the process aid parameters.

[c2] 2. The method of claim 1, wherein the building step includes building the process aid in one of a kerf and a sacrificial die on the wafer.

[c3] 3. The method of claim 1, wherein the instructions include scheme code.

[c4] 4. The method of claim 1, further comprising the step of documenting the process aid.

[c5] 5. The method of claim 4, wherein the documentation includes process aid location.

[c6] 6. The method of claim 1, further comprising at least one of the steps of verifying the process aid against production data and testing the process aid.

[c7] 7. The method of claim 1, further comprising the step of rerunning the step of building.

[c8] 8. A system for generating a process aid on a wafer, the system comprising:

means for entering a process technology and a process aid type into a program;

means for reading technology design rules and process aid parameters for the process aid into the program;

means for accessing a process aid instruction file to attain instructions for building the process aid; and

means for building the process aid on the wafer using the instructions based on the technology design rules and process aid parameters.

[c9] 9. The system of claim 8, wherein the process aid is one of an electrical device and an optical device.

[c10] 10. The system of claim 8, wherein the instructions include scheme code.

[c11] 11. The system of claim 8, further comprising means for

documenting the process aid.

[c12] 12. The system of claim 11, wherein the documentation includes process aid location.

[c13] 13. The system of claim 8, further comprising means for verifying the process aid against production data.

[c14] 14. The system of claim 8, further comprising means for testing the process aid.

[c15] 15. A computer program product comprising a computer useable medium having computer readable program code embodied therein for generating a process aid on a wafer, the program product comprising:

program code configured to allow entering a process technology and the process aid type;

program code configured to read technology design rules and process aid parameters for the process aid;

program code configured to access a process aid instruction file to attain instructions for building the process aid; and

program code configured to build the process aid on the wafer using the instructions based on the technology design rules and process aid parameters.

[c16] 16. The program product of claim 15, wherein the process aid is one of an electrical device and an optical de-

vice.

[c17] 17. The program product of claim 15, wherein the instructions include scheme code.

[c18] 18. The program product of claim 15, further comprising program code configured to document the process aid.

[c19] 19. The program product of claim 15, further comprising program code configured to verify the process aid against production data.

[c20] 20. The program product of claim 15, further comprising program code configured to test the process aid.